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APPLICANTS									
Warren M. Far	nworth, Nampa, ID;								
Malcolm Grief,	Boise, ID;								
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Foreign Priority claimed	□ yes 🗫no		STATE OR	SH	EETS	τc	TAL	INDEPENDENT	
35 USC 119 (a-d) conditions met yes no Met after Allowance Verified and Acknowledged Examiner's Signature Initials			COUNTRY		DRAWING C		AIMS 11	CLAIMS 1	
ADDRESS 021567 WELLS ST. JOHN P. 601 W. FIRST AVENI SPOKANE, WA 99201									
TITLE Method and apparatus operability	for testing semiconductor circui	try for operabi	lity and method of	forming a	pparatus fo	or testing	semicono	ductor circuitry for	
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FILING FEE	FEES: Authority has been given in Paper Noto charge/credit DEPOSIT ACCOUNT Nofor following:				☐ 1.16 Fees (Filing) ☐ 1.17 Fees (Processing Ext. of time) ☐ 1.18 Fees (Issue)				
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